Mitutoyo

SURFTEST SJ-410 SERIES

PORTABLE SURFACE ROUGHNESS TESTER EVOLUTION.

FORM MEASUREMENT

Portable Surface Roughness Tester Evolves!

Enhanced power for making measurements on site

Colour-graphic LCD

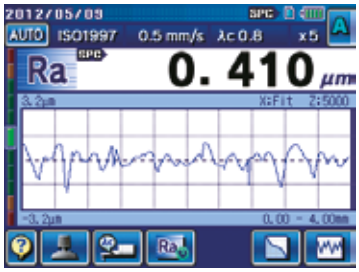
The colour-graphic LCD with excellent visibility displays calculated results and assessed profiles even clearer. This is really useful for checking results without printing them out.

Backlight provided

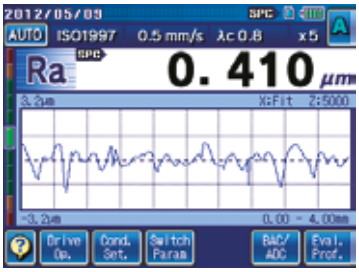
A backlight improves usability in dim testing environments.

Touch screen for easier operations

The screen display can be switched between icon display and text display. Successfully realizes operability with utility and usability.



Icon display

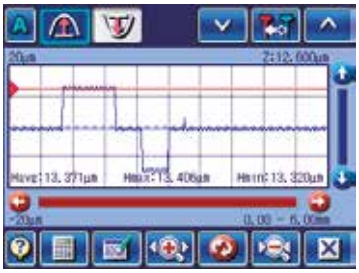


Text display

Easy to use and highly functional

This portable surface roughness tester is equipped with analysis functionality rivaling that of benchtop surface roughness testers.

Data compensation


Simple contour analysis function

Applicable standards

Complies with many industry standards

The Surftest SJ-410 complies with the following standards: EN ISO, VDA, JIS, ANSI as well as customized settings.

Multilingual support

The display interface supports 16 languages.

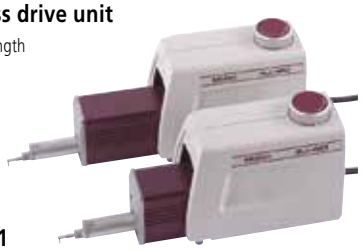
High accuracy measuring

A wide range, high-resolution detector

Measuring range / resolution
800 µm/0.0125 µm
80 µm/0.00125 µm
8 µm/0.000125 µm

High straightness drive unit

Straightness / traverse length
0.3 µm/25 mm (SJ-411)
0.5 µm/50 mm (SJ-412)


SJ-412

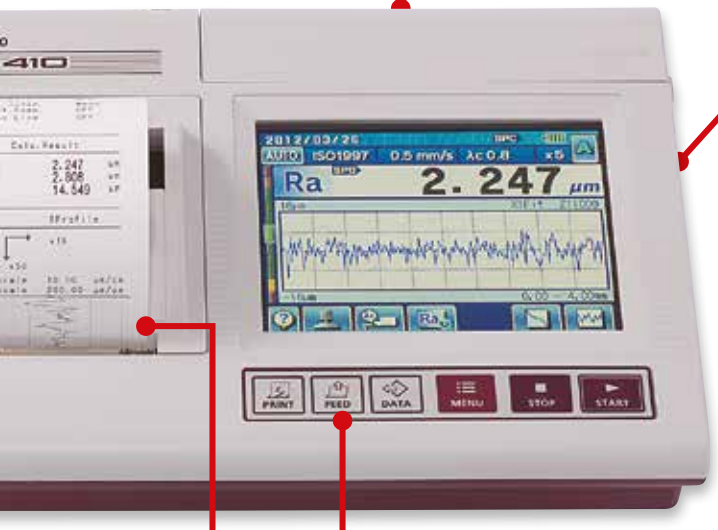
SJ-411

The Large Touch-screen, Colour-graphic LCD Ensures Both Intuitive Control and Advanced Operability

Interfaces

A variety of interfaces supplied as standard

The external device interfaces that come as standard include USB, RS-232C, SPC output and footswitch I/F.



Data storage

Memory card (optional) is supported

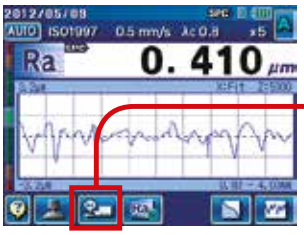
The measurement conditions and data can be stored in a memory card (optional) and recalled as required. This enables batch analysis and printout of data after on-site measurement.

- **Measurement condition**
  Internal memory: 10 sets
  Memory card: 500 sets
- **Measurement result**
  Memory card: 1000 sets

Password protection

Access to functions can be restricted by a password

A pre-registered password can limit use of measurement conditions and other settings to the tester's administrator.



Sheet buttons

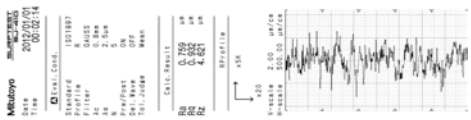
Single button measurements

A sturdy sheet-button panel with superior durability in any environment is provided. For repeat measurement of the same work, simply pressing the start switch can complete measurement, analysis and printout.

Printer

High-speed printer prints out measurement results on site

A high-quality, high-speed thermal printer prints out measurement results. It can also print a BAC curve or an ADC curve as well as calculated results and assessed profiles. These results and profiles are printed out in landscape format, just as they appear on the color-graphic LCD.



Carrying case

The unit is easily transported in a dedicated carrying case which includes holders for the accessories as well as the tester itself (standard accessory).

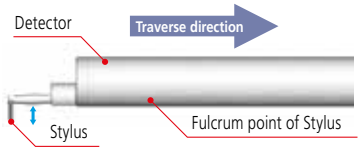
Enhanced Measuring Functions

Your choice of skidless or skidded measurement

Patent registered in Japan, U.S.A.. Patent pending in Germany

• Skidless measurement

Skidless measurement is where surface features are measured relative to the drive unit reference surface. This measures waviness and finely stepped features accurately, in addition to surface roughnness, but range is limited to the stylus travel available. The SJ-410 series supports a variety of surface feature measurements simply by replacing the stylus.

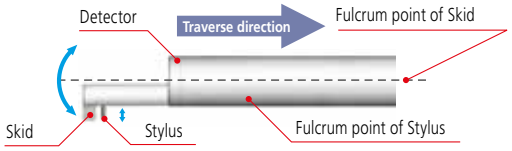


Measuring example of stepped features: Skidless

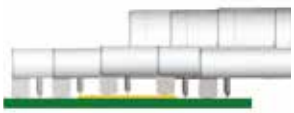
Measured profile

• Skidded measurement

In skidded measurements, surface features are measured with reference to a skid following close behind the stylus. This cannot measure waviness and stepped features exactly but the range of movement within which measurement can be made is greater because the skid tracks the workpiece surface contour.



Measuring example of stepped features: Skidded



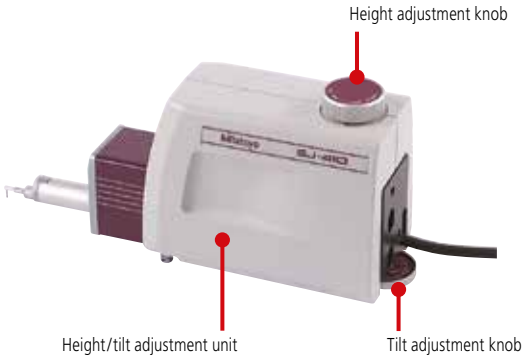
Measured profile

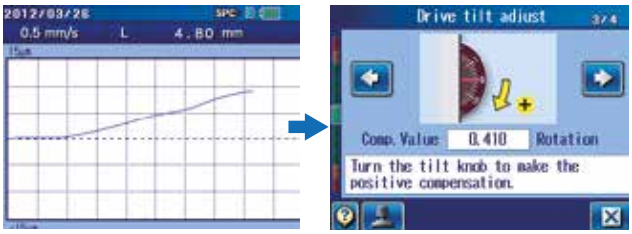
Powerful support for leveling

Patent registered in Japan, U.S.A.. Patent pending in Germany

The height/tilt adjustment unit comes as standard for leveling the drive unit prior to making skidless measurements and, supported by guidance from the unique D.A.T. function, makes it easy to achieve highly accurate alignment.

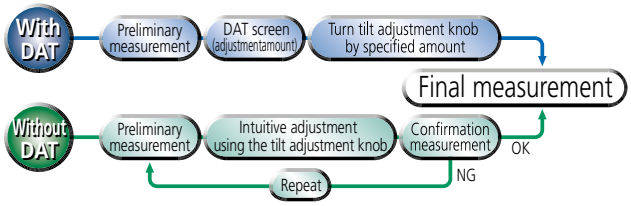
• Height/tilt adjustment unit (standard accessory)





Preliminary measurement

Amount of tilt adjustment

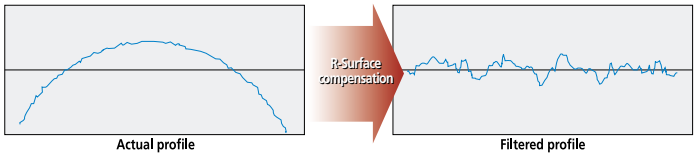


When the SJ-410 Series detector is mounted on the manual column stand*1 for measurement, it can be combined with any of the optional products for easier leveling: leveling table*1, 3-axis alignment table*1 or tilt adjustment unit*1.

*1: For details about optional products, see P6-7.

More measuring functions than expected from a compact tester

Usually, a spherical or cylindrical surface (R-surface) cannot be evaluated, but, by removing the radius with a filter, R-surface data is processed as if taken from a flat surface.

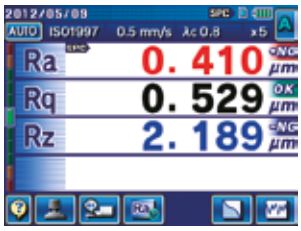


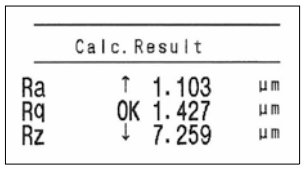
Recalculating

Previously measured data can be recalculated for use in other evaluations by changing the current standard, assessed profile and roughness parameters.

GO/NG judgement function

An "OK/NG" judgment symbol is displayed when limits are set for the roughness parameter. In case of "NG," the calculated result is highlighted. The calculated result can also be printed out.





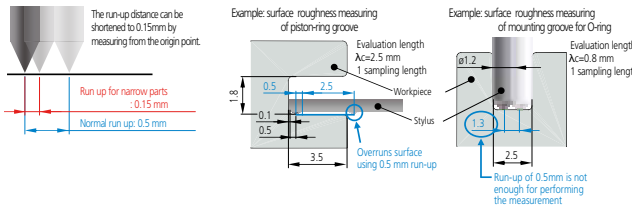
The "OK" symbol means the measurement is within the limits set; "NG" means it is not, in which case an arrow points to either the upper or lower limit in the printout.

Narrow space measuring function

Patent pending in Japan

Surface roughness measurement requires a run-up distance before starting the measurement (or retrieving data). When the SJ-410 Series measures, its run-up distance is normally set to 0.5 mm. This distance, however, can be shortened to 0.15 mm using the narrow part measurement function (starting from the origin point of the drive unit). The function extends the possibility of measurement of narrow locations such as grooves in piston ring / O-ring mounts.

•Narrow space measuring Typical applications



Real sampling

This function samples stylus displacement for a specified time without engaging detector traverse, which enables use as a simplified vibration meter or displacement gage incorporated in another system.

Assessing a single measurement result under two different evaluation conditions

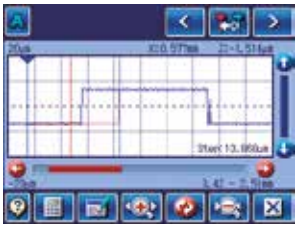
A single measurement enables simultaneous analysis under two different evaluation conditions. A single measurement allows calculation of parameters and analysis of assessed profiles without the need for recalculation after saving data, contributing to higher work efficiency.

Arbitrary sampling length setting

This function allows a sampling length to be arbitrarily set in 0.01 mm increments (**SJ-411**: 0.1 mm to 25 mm, **SJ-412**: 0.1 mm to 50 mm). It also allows the **SJ-410** series to make both narrow and wide range measurements.

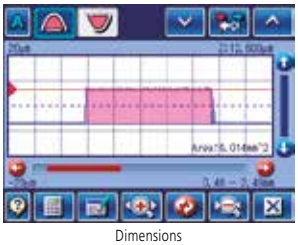
Simple contour analysis function

Point group data collected for surface roughness evaluation is used to perform simplified contour analysis (step, step height, area and coordinate variation). It assesses minute forms that cannot be assessed by a contour measurer.

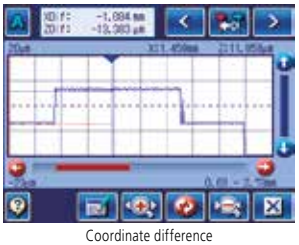


Step

Step volume



Dimensions



Coordinate difference

Optional Accessories

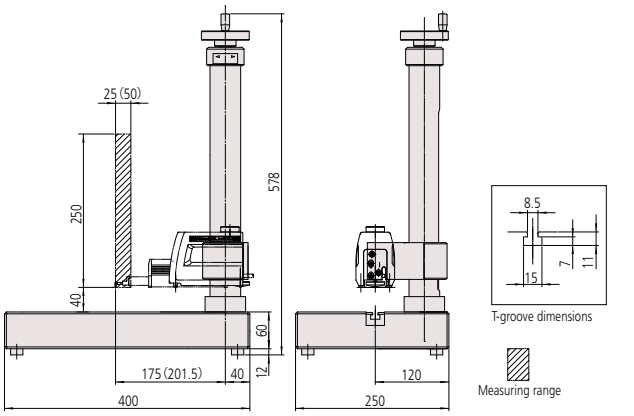
Simple column stand

Can be adjusted to match the height of the item to be measured.

No.178-039
Vertical adjustment range: 250 mm
Dimensions: 400 × 250 × 578 mm
Mass: 20 kg

Example of mounting on simple column stand

Unit: mm



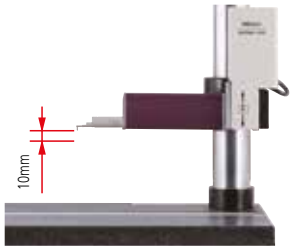
*The dimensions in parentheses indicate those for **SJ-412**

Options for simple column stand

Three new optional products are available to be attached to the manual column stand (No.178-039). You can choose the unit that suits your application. Or, you can also use the three products in any combination. Using the optional units makes SJ-411/412 more convenient and easier to use to ensure accurate measurements.

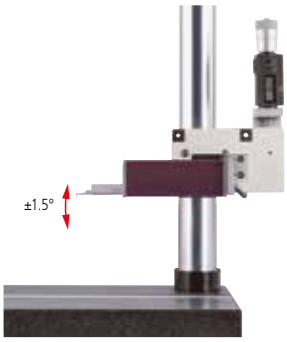
Auto-set unit* – 178-010

This unit enables the vertical (Z-axis) direction to be positioned automatically (auto-set function). A single button operation completes a series of operations from measurement, saving and auto-return (saving and auto-return can be switched on and off by operating the drive unit).

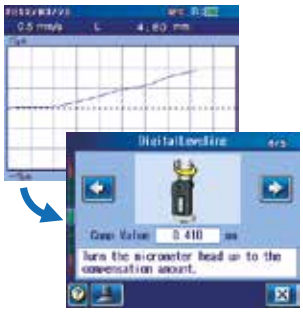


Tilting adjustment unit* – 178-030

This unit is used for aligning the workpiece surface with the detector reference plane. It supports the DAT function to make the leveling of workpiece surfaces easier.



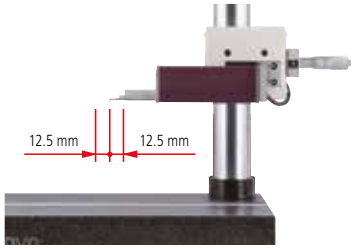
Preliminary measurement



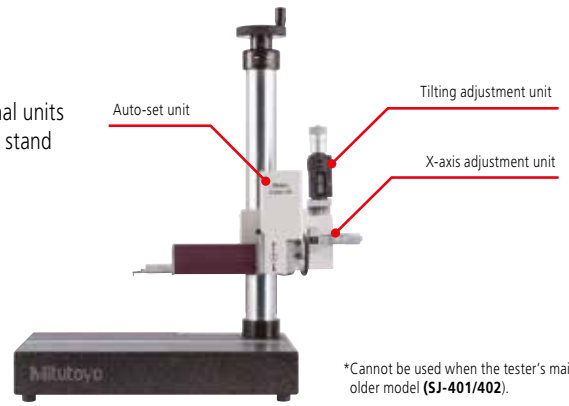
Tilt adjustment

X-axis adjustment unit* – 178-020

This unit helps fine-tune the horizontal (X-axis) direction.



Complete set of optional units for the manual column stand

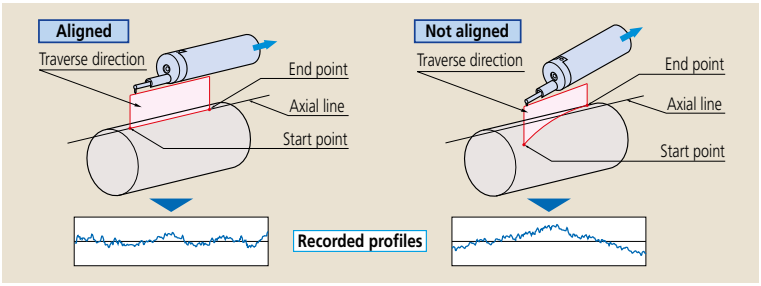


*Cannot be used when the tester's main unit is an older model **(SJ-401/402)**.

3-axis adjustment table: 178-047

Patent registered in Japan, U.S.A.. Patent pending in Germany

This table helps make the alignment adjustments required when measuring cylindrical surfaces. The corrections for the pitch angle and the swivel angle are determined from a preliminary measurement and the digimatic micrometers are adjusted accordingly. A flat-surfaced workpiece can also be leveled with this table.

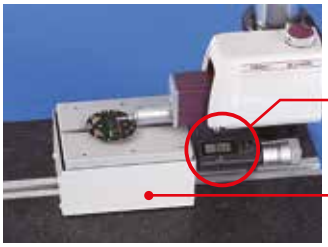


DAT function for the optional leveling table

Patent registered in Japan, U.S.A.. Patent pending in Germany

The leveling table can be used to align the surface to be tested with the detector reference plane. The operator is guided through the procedure by screen prompts.

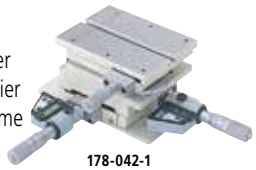
No.178-048
Inclination adjustment angle: ± 1.5°
Table dimensions: 130 x 100 mm
Maximum load: 15 kg



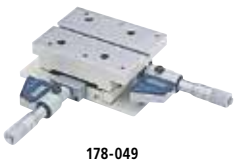
DAT screen guides the user when leveling

XY leveling tables

The table includes X- and Y-axes micrometer heads. This makes axis alignment much easier because the tilt adjustment center is the same as the rotation center of the table.
(Code **No.178-042-1/178-043-1**)

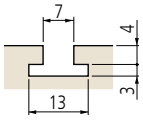


178-042-1



178-049
(Movement is in X- and Y-axes only.)

Order No.	**178-042-1**(mm) **178-052-1**(inch) *with digital heads	**178-043-1**(mm) **178-053-1**(inch) *with analog heads	**178-049**(mm) **178-058**(inch/mm) *with digital heads
Table dimensions	130 x 100 mm		
Maximum load	15 kg		
Inclination adjustment angle	±1.5°		—
Swiveling angle	±3°		—
X/Y-axis travel range	±12.5 mm	±12.5 mm	±12.5 mm
Resolution	0.001 mm	0.01 mm	0.001 mm
Dimensions (WxDxH)	262 x 233 x 83 mm	220 x 189 x 83 mm	262 x 233 x 55 mm
Mass	6.3 kg	6 kg	5 kg



T-groove dimensions

Precision vise

Fits on the stand.

Application

Order No.	178-019
Clamping method	Sliding jaws
Jaw opening	36 mm
Jaw width	44 mm
Jaw depth	16 mm
Height	38 mm

Cylinder attachment

This block can be positioned on top of cylindrical objects to perform measurements.

No.12AAB358
Diameter: ø 15~60 mm

Configuration:

- Cylindrical measurement block
- Auxiliary block
- Clamp

*Drive unit not included.

Reference step specimen

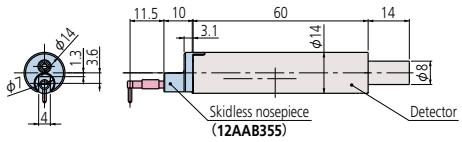
Used to calibrate detector sensitivity.

No.178-611
Step nominal values: 2 µm /10 µm

Optional Accessories: Detectors / Styli

Detectors

Unit: mm

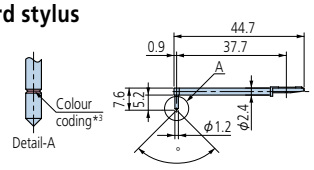


Order No.	Measuring force
178-396-2	0.75 mN
178-397-2	4 mN

Styli

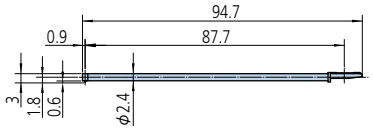
Unit: mm

Standard stylus



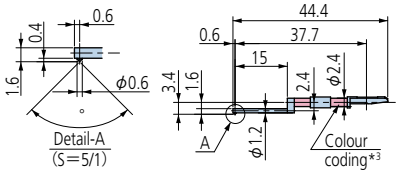
12AAE882 (R1 µm - 60°)
12AAE924 (R1 µm - 90°)
12AAC731 (R2 µm - 60°)
12AAB403 (R5 µm - 90°)
12AAB415 (R10 µm - 90°)
12AAE883 (R250 µm*2 - 60°)
( ): Tip radius - Tip angle

Double-length for deep hole *1



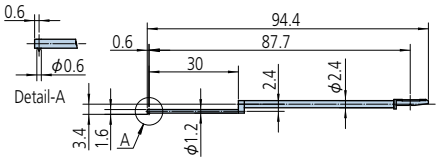
12AAE898 (R2 µm - 60°)
12AAE914 (R5 µm - 90°)

For small hole



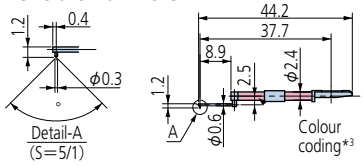
12AAC732 (R2 µm - 60°)
12AAB404 (R5 µm - 90°)
12AAB416 (R10 µm - 90°)

For small hole / Double-length for deep hole*1



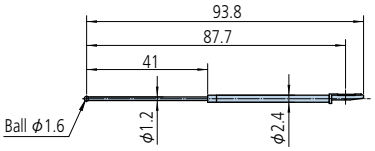
12AAE892 (R2 µm - 60°)
12AAE908 (R5 µm - 90°)

For extra-small hole



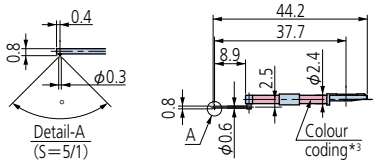
12AAC733 (R2 µm - 60°)
12AAB405 (R5 µm - 90°)
12AAB417 (R10 µm - 90°)

For small hole *1 *2



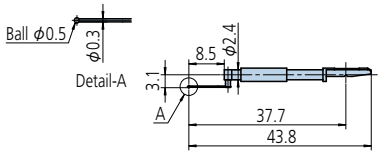
12AAE884 (R0,8 mm)

For ultra-small hole



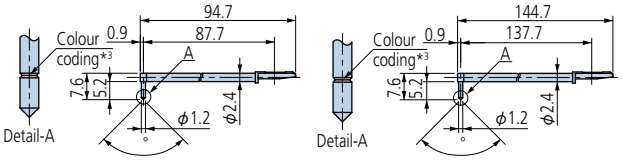
12AAC734 (R2 µm - 60°)
12AAB406 (R5 µm - 90°)
12AAB418 (R10 µm - 90°)

For ultra-small hole *2



12AAJ662 (R0,25 mm)

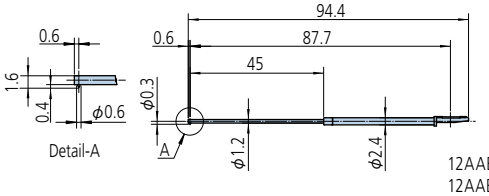
For deep hole (double-length and triple-length) *1



2X stylus
12AAC740 (R2 µm - 60°)
12AAB413 (R5 µm - 90°)
12AAB425 (R10 µm - 90°)

3X stylus
12AAC741 (R2 µm - 60°)
12AAB414 (R5 µm - 90°)
12AAB426 (R5 µm - 90°)

For small slotted hole *1



12AAE938 (R2 µm - 60°)
12AAE940 (R5 µm - 90°)

*1: For downward-facing measurement only.
*2: Used for calibration, a standard step gauge (No.178-611, option) is also required

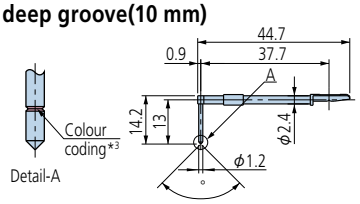
*3:

Tip radius	1 µm	2 µm	5 µm	10 µm	250 µm
Color coding	White	Black	No color	Yellow	No notch or color

Styli

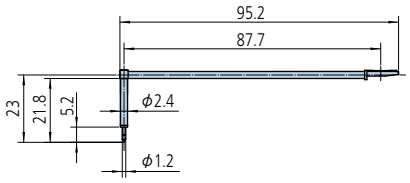
Unit: mm

For deep groove(10 mm)



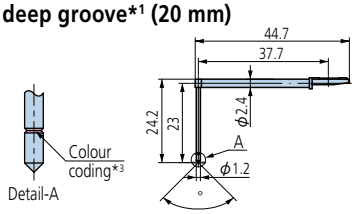
12AAC735 (R2 µm - 60°)
12AAB409 (R5 µm - 90°)
12AAB421 (R10 µm - 90°)

For deep groove *1 (20 mm)



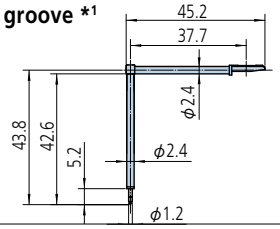
12AAE893 (R2 µm - 60°)
12AAE909 (R5 µm - 90°)

For deep groove*1 (20 mm)



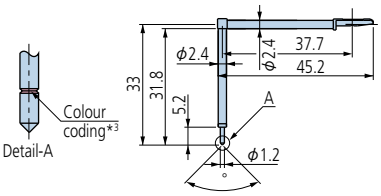
12AAC736 (R2 µm - 60°)
12AAB408 (R5 µm - 90°)
12AAB420 (R10 µm - 90°)

For deep groove *1 (40 mm)



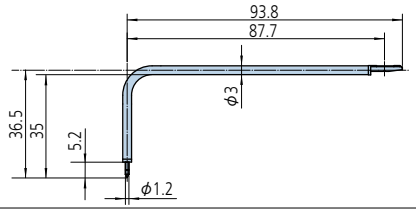
12AAE895 (R2 µm - 60°)
12AAE911 (R5 µm - 90°)

For deep groove*1 (30 mm)



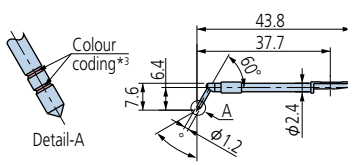
12AAC737 (R2 µm - 60°)
12AAB407 (R5 µm - 90°)
12AAB419 (R10 µm - 90°)

For deep groove (30 mm) / Double-length for deep hole *1



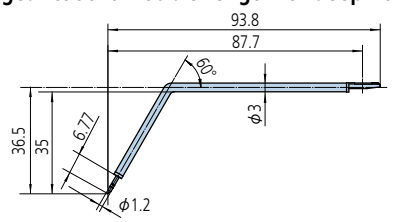
12AAE894 (R2 µm - 60°)
12AAE910 (R5 µm - 90°)

For gear tooth



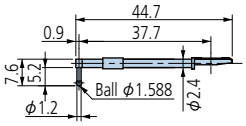
12AAB339 (R2 µm - 60°)
12AAB410 (R5 µm - 90°)
12AAB422 (R10 µm - 90°)

For gear tooth / Double-length for deep hole *1



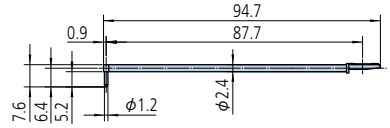
12AAE896 (R2 µm - 60°)
12AAE912 (R5 µm - 60°)

For rolling circle waviness surface *2



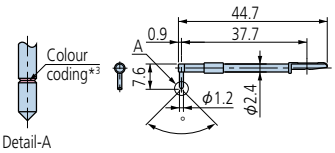
12AAB338 (ø 1.588 mm)

For rolling circle waviness / Double-length for deep hole *1 *2



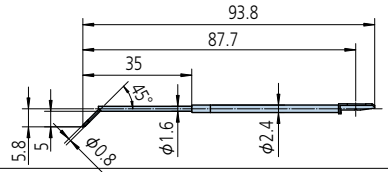
12AAE886 (R250 µm - 60°)

For knife-edge *2



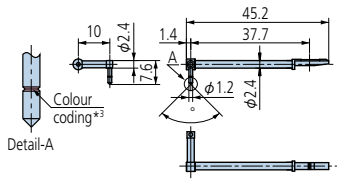
12AAC738 (R2 µm - 60°)
12AAB411 (R5 µm - 90°)
12AAB423 (R10 µm - 90°)

For corner hole / Double-length for deep hole *1



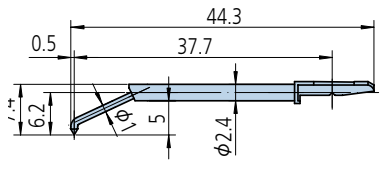
12AAM601 (R2 µm - 60°)
12AAM603 (R5 µm - 60°)

For eccentric arm *1



12AAC739 (R2 µm - 60°)
12AAB412 (R5 µm - 90°)
12AAB424 (R10 µm - 90°)

For hole bottom



12AAE899 (R2 µm - 60°)
12AAE915 (R5 µm - 90°)

*1: For downward-facing measurement only. Customized special interchangeable styli are available on request, please contact any Mitutoyo office for more information.
*2 : Used for calibration, a standard step gauge (No.178-611, option) is also required

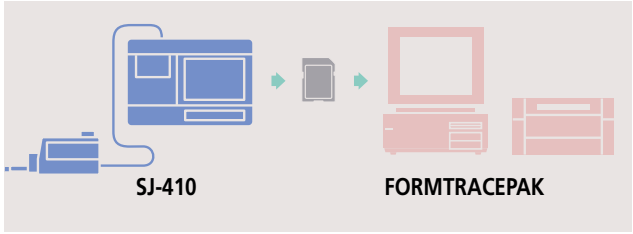
*3

Tip radius	2 µm	5 µm	10 µm
Colour coding	Black	No colour	Yellow

Optional Accessories: For External Output

Contour / Roughness analysis software FORMTRACEPAK

More advanced analysis can be performed by loading SJ-410 series measurement data to software program FORMTRACEPAK via a memory card (option) for processing back at base.



Measurement Data Wireless Communication System U-WAVE

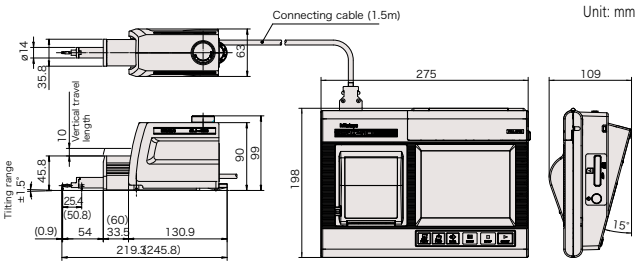
This unit allows you to remotely load Surftest SJ-410 calculation results (SPC output) into commercial spreadsheet software on a PC. You can essentially use a one-touch operation to enter the calculation results (values) into the cells in the spreadsheet software.

U-WAVE-R
(Connects to the PC)
No.02AZD810D

U-WAVE-T*
(Connects to the SJ-410)
No.02AZD880D

*Requires the optional Surftest SJ-410 connection cable.
No.02AZD790D

Unit: mm



*The dimensions in parentheses indicate those for SJ-412

Simplified communication program for SURFTEST SJ series

The Surftest SJ-410 series has a USB interface, enabling data to be transferred to a spreadsheet or other software. We also provide a program that lets you create inspection record tables using a Excel® macro.

This program can be downloaded free of charge from the Mitutoyo website.
http://www.mitutoyo.eu

Required environment

OS: Windows XP-SP3
Windows Vista
Windows 7
Windows 8
Windows 10

Spreadsheet software: Microsoft®Excel® 2000
Microsoft®Excel® 2002
Microsoft®Excel® 2003
Microsoft®Excel® 2007
Microsoft®Excel® 2010
Microsoft®Excel® 2013

The optional USB cable is also required.

- USB cable for SJ-410 series **No.12AAD510**

Digimatic mini processor DP-1VR

This unit allows you to load Surftest SJ-410 calculation results (SPC output) into commercial spreadsheet software on a PC via a USB connector. You can essentially use a one-touch operation to enter the calculation results (values) into the cells in the spreadsheet software.

USB Input Tool Direct
USB-ITN-D
No.06ADV380D

USB keyboard signal conversion type*
IT-016U
No.264-016
* Requires the optional Surftest SJ-410 connection cable.
1 m: **No.936937**
2 m: **No.965014**

Specifications

Model No.		SJ-411		SJ-412	
Order No.	mm	178-580-01	178-580-02	178-582-01	178-582-02
	inch/mm	178-581-01	178-581-02	178-583-01	178-583-02
Measuring range	X-axis	**25 mm** (1 inch)		**50 mm** (2 inch)	
	Z1-axis (detector unit)	800 µm, 80 µm, 8 µm *Up to 2,400 µm with an optional stylus			
Detector	Measuring principle	Differential inductance			
	Resolution	**0.01 µm (800 µm range) / 0.001 µm (80 µm range) / 0.0001 µm (8 µm range)** 0.4 µinch (32000 µinch) / 0.04 µinch (3200 µinch) / 0.004 µinch (320 µinch)			
	Stylus tip	60°/**2 µm** (80 µinch)	90°/**5 µm** (200 µinch)	60°/**2 µm** (80 µinch)	90°/ **5 µm** (200 µinch)
	Measuring force	0.75 mN	4 mN	0.75 mN	4 mN
	Radius of skid curvature	**R40 mm** (R1.57")			
	Measuring method	Skidded measurement / skidless measurement			
Drive unit: X-axis	Measuring speed	**0.05, 0.1, 0.2, 0.5, 1.0 mm/s** (0.002, 0.004, 0.008, 0.02, 0.04 inch/s)			
	Drive speed	**0.5, 1, 2, 5 mm/s** (0.02, 0.04, 0.08, 0.2 inch/s)			
	Straightness	**0.3 µm / 25 mm** (12 µinch / 1 inch)		**0.5 µm / 50 mm** (20 µinch / 2 inch)	
Height-tilt adjustment unit	Height adjustment	**10 mm** (0.39 inch)			
	Tilt adjustment	± 1.5°			
Standards		JIS1982 / JIS1994 / JIS2001 / ISO1997 / ANSI / VDA			
Parameters		Ra, Rq, Rz, Ry, Rp, Rv, Rt, R3z, Rsk, Rku, Rc, RPc, RSm, Rmax*1, Rz1max*2, S, HSC, RzJIS*3, Rppi, RΔa, RΔq, Rlr, Rmr, Rmr(c), Rσc, Rk, Rpk, Rvk, Mr1, Mr2, A1, A2, Vo, λa, λq, Lo, Rpm, tp*4, Htp*4, R, Rx, AR, W, AW, Wx, Wte, Possible Customize			
Measured profiles		Primary, Roughness, DF, Filtered waviness curve, R-Motif, W-Motif			
Graph analysis		BAC and ADC curves			
Data compensation		Parabola / Hyperbola / Ellipse / Circle / Conic / Tilting, Compensation off			
Filter		2CR, PC75, Gaussian filter			
Cut-off length	λ_c	0.08, 0.25, 0.8, 2.5, 8.0 mm			
	λ_s*5	**2.5, 8.0, 25 µm** (100, 320, 1000 µinch)			
Sample length		0.08, 0.25, 0.8, 2.5, 8.0, 25.0 mm			
Number of sampling lengths		x1, x2, x3, x4, x5, x6, x7, x8, x9, x10, x11, x12, x13, x14, x15, x16, x17, x18, x19, x20			
Arbitrary length		0.1~25 mm		0.1~50 mm	
Functions	Customization	Desired parameters can be selected for calculation and display			
	Simple contour analysis function	Step, step volume, dimensions, coordinate difference			
	DAT function	Helps to adjust leveling during skidless measurement			
	Real sampling function	Samples stylus displacement for a specified time without engaging detector traverse.			
	Statistical processing	Static measurement (max. 3 parameters) is possible. Static processing for MAX, MIN, AVERAGE, standard deviation, histogram and pass rate is possible			
	GO/ NG judgement*6	Max rule / 16 % rule / Average rule / Standard deviation (1σ, 2σ, 3σ)			
	Storage functions	10 measuring conditions can be stored in internal memory			
	Printing function	Measurement conditions / Calculation results / GO / NG judgement result / Calculation results for each sampling length / Measurement curve / BAC / ADC / Environmental setting information			
	Display languages	Japanese, English, German, French, Italian, Spanish, Portuguese, Korean, Traditional Chinese, Simplified Chinese, Czech, Polish, Hungarian, Turkish, Swedish, Dutch			
	Storage	Internal memory: Measurement condition (10 sets) Memory card (option): 500 measurement condition, 10000 measuring data, 10000 text data, 500 statistic data, 1 backup of machine setting, the last ten traces (Trace 10)			
	External I/O	USB I/F, Digimatic output, RS-232C I/F, External SW I/F			
Power supply	Battery	Two-way power supply: battery (rechargeable Ni-MH battery) and AC adapter Charging time: about 4 hours (may vary due to ambient temperature) Endurance: about 1500 measurements (differs slightly due to use conditions / environment)			
	Power consumption	50 W			
Size (WxDxH)	Display unit	**275×198×109 mm** (10.83×4.29×7.80 inch)			
	Height adjustment unit	**130.9×63×99 mm** (5.16×2.48×3.90 inch)			
	Drive unit	**128×35.8×46.6 mm** (5.04×1.41×1.83 inch)		**154.5×35.8×46.6 mm** (6.08×1.41×1.83 inch)	
Mass	Display unit	1.7 kg			
	Height adjustment unit	0.4 kg			
	Drive unit	0.6 kg		0.64 kg	
Standard accessories		Detector*7, Stylus*8, Roughness specimen **270732** Printing paper **12BAL402** Touch-screen protection sheet **12BAG834** Touch pen **12AAN041** Carrying case AC adapter, Philips screwdriver, Strap for stylus pen, Operation manual, Quick reference manual, Warranty			

*1: Only for VDA/ANSI/JIS'82 standards.
*2: Only for ISO'97 standard.
*3: Only for JIS'01 standard.
*4: Only for ANSI standard.
*5: λs may not be switchable depending on standard selected.
*6: Standard deviation only can be selected in ANSI.16% rule cannot be selected in VDA.
*7: Either **No.178-396** or **No.178-397** is supplied as a standard accessory depending on the Order No. of the main unit for SJ-410 Series.
*8: The standard stylus (**No.12AAC731** or **No.12AAB403**), which is compatible with the detector supplied, is a standard accessory.
To denote your AC line voltage add the following suffixes (e.g. **178-570-01A**).
A for 120V, C for 100V, D for 230V, E for 230V (for UK), DC for 220V (for China), K for 220V (for Korea)

Optional accessories, consumables, and others for SJ-410

• Printer paper (5 rolls)	**No.270732**
• Touch-screen protector sheet (10 sheets)	**No.12AAN040**
• Memory card (2GB) *	**No.12AAL069**
• Connecting cable (for RS-232C)	**No.12AAA882D**

* micro SD card (with a conversion adapter to SD card)

Coordinate Measuring Machines

Vision Measuring Systems

Form Measurement

Optical Measuring

Sensor Systems

Test Equipment and Seismometers

Digital Scale and DRO Systems

Small Tool Instruments and Data Management

Whatever your challenges are, Mitutoyo supports you from start to finish.

Mitutoyo is not only a manufacturer of top quality measuring products but one that also offers qualified support for the lifetime of the equipment, backed up by comprehensive services that ensure your staff can make the very best use of the investment.

Apart from the basics of calibration and repair, Mitutoyo offers product and metrology training, as well as IT support for the sophisticated software used in modern measuring technology. We can also design, build, test and deliver bespoke measuring solutions and even, if deemed cost-effective, take your critical measurement challenges in-house on a sub-contract basis.

Find additional product literature and our product catalogue

www.mitutoyo.eu

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